

Notice of References Cited	Application/Control No. 10/648,782	Applicant(s)/Patent Under Reexamination TAKAYAMA ET AL.	
	Examiner JOHN J. LEE	Art Unit 2618	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0040334	02-2003	Lee, Jae Kyung	455/557
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NON-PATENT DOCUMENTS

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